



JOURNAL OF SOLID STATE CHEMISTRY

Journal of Solid State Chemistry 178 (2005) 1721

www.elsevier.com/locate/jssc

Announcement

2nd International Symposium on Point Defect and Nonstoichiometry Kaohsiung, Taiwan, October 4–6, 2005

This symposium is aimed at reporting advances on every aspect of compositional defects, including non-stoichiometry and related point defects, in materials and relevant technologies. The materials covered include semiconductors, oxides (ceramics, dielectrics, etc.), in fact any multinary inorganic material, whether in bulk, thin film, or nano-structure form.

The goal of the symposium is to stimulate interactions between engineers and scientists in an effort to bridge the usual gaps between different disciplines. It will emphasize novel approaches and methods of identification and distribution of defects on the atomic scale in relation to the physical properties of the material. In addition to bulk stoichiometry and its effects on various devices, the symposium will focus on surface stoichiometry in relation to surface reactivity (interfacial trap charges) and segregation (formation of quantum dots), emerging fields of interest for nano-scale materials and processes. Papers are solicited on a wide variety of topics including, but not limited to, the following:

- 1. Non-stoichiometry-related defect characterization and material properties
- 2. Growth and characterization of single crystals
- 3. Thin films, interfaces, and structural defects (material design/characterization, composition analysis)
- 4. Diffusion modeling and characterization
- 5. Defect structures and formation mechanisms
- 6. Electronic and optical devices
- 7. High-k dielectrics
- 8. Formation mechanisms of nano dots and wires
- 9. Trap states in amorphous semiconductor (for solar cell/TFT, etc.)
- 10. Defect modeling and simulations

The conference includes oral and poster sessions of contributed papers, and invited lectures comprising reviews on topics of current importance.

The deadline for abstract submission is May 15, 2005.

For further information, please contact:

Conference Secretary: Prof. Mitch M.C. Chou Department of Materials Science and Optoelectronic Engineering National Sun Yat-Sen University

Kaohsiung 804, Taiwan Phone: +886-7-5252000 ext. 4078

Fax: +886-7-5254099

E-mail: mitch@mail.nsysu.edu.tw

Web site: www.mse.nsysu.edu.tw/ispn2005